# **TPC8209**

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOS II)

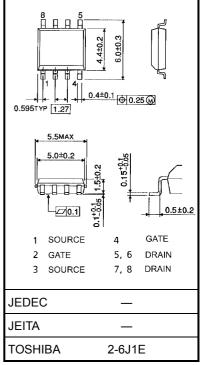
# **TPC8209**

Lithium Ion Battery Applications Portable Equipment Applications Notebook PC Applications

- Small footprint due to small and thin package
- Low drain-source ON resistance:  $R_{DS}$  (ON) = 30 m $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 10 \text{ S} (typ.)$
- Low leakage current:  $I_{DSS} = 10 \ \mu A \ (max) \ (V_{DS} = 30 \ V)$
- Enhancement-mode:  $V_{th} = 1.3$  to 2.5 V ( $V_{DS} = 10$  V,  $I_D = 1$  mA)

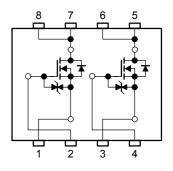
# Maximum Ratings (Ta = 25°C)

Char	acteristics	Symbol	Rating	Unit	
Drain-source vol	tage	V <sub>DSS</sub>	30	V	
Drain-gate voltag	ge (R <sub>GS</sub> = 20 k Ω )	V <sub>DGR</sub>	30	V	
Gate-source volt	age	V <sub>GSS</sub>	±20	V	
Drain current	D C (Note 1)	I <sub>D</sub>	5	А	
Drain current	Pulse (Note 1)	I <sub>DP</sub>	20	~	
Drain power dissipation (t = 10s) (Note 2a)	Single-device operation (Note 3a)	P <sub>D (1)</sub>	1.5	W	
	Single-device value at dual operation (Note 3b)	P <sub>D(2)</sub>	1.1		
Drain power dissipation (t = 10s) (Note 2b)	Single-device operation (Note 3a)	P <sub>D (1)</sub>	0.75	W	
	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>	0.45		
Single pulse ava	lanche energy (Note 4)	E <sub>AS</sub>	32.5	mJ	
Avalanche curre	nt	I <sub>AR</sub>	5	А	
Repetitive avalar Single-device va	nche energy lue at dual operation (Note 2a, 3b, 5)	E <sub>AR</sub>	0.1	mJ	
Channel tempera	ature	T <sub>ch</sub>	150	°C	
Storage tempera	iture range	T <sub>stg</sub>	-55~150	°C	



Weight: 0.08 g (typ.)

# **Circuit Configuration**



Note: For (Note 1), (Note 2), (Note 3) and (Note 4), please refer to the next page.

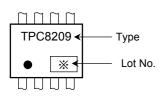
This transistor is an electrostatic sensitive device. Please handle with caution.

Unit: mm

# **Thermal Characteristics**

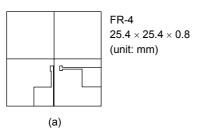
Characteristics	Symbol	Max	Unit		
Thomas acidence abound to embiant	Single-device operation (Note 2a)	R <sub>th (ch-a)</sub> (1)	83.3		
Thermal resistance, channel to ambient (t = 10s) (Note 1a)	Single-device value at dual operation (Note 2b)	R <sub>th (ch-a) (2)</sub>	114	°C/W	
Thermal resistance, channel to ambient	Single-device operation (Note 2a)	R <sub>th (ch-a) (1)</sub>	167	C/VV	
(t = 10s) (Note 2b)	Single-device value at dual operation (Note 2b)	R <sub>th (ch-a) (2)</sub>	278		

# Marking (Note 6)

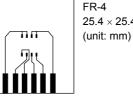


Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:



a) Device mounted on a glass-epoxy board (a)



 $25.4\times25.4\times0.8$ 



Device mounted on a glass-epoxy board (b) b)

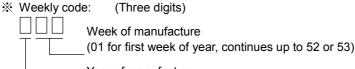
#### Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device. (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device. (During dual operation, power is evenly applied to both devices.)

Note 4:  $V_{DD}$  = 24 V,  $T_{ch}$  = 25°C (initial), L = 1.0 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 5 A

Note 5: Repetitive rating: pulse width limited by maximum channel temperature

Note 6: • on lower left of the marking indicates Pin 1.



Year of manufacture (One low-order digits of calendar year)

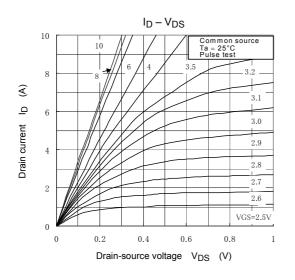
Electrical Characteristics (Ta = 25°C)

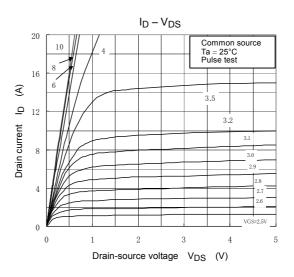
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μA
Drain cut-OFF curre	nt	I <sub>DSS</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V		_	10	μA
Drain-source breakdown voltage		V (BR) DSS	$I_{D}$ = 10 mA, $V_{GS}$ = 0 V	S = 0 V 30 -	—	V	
Dialit-Source break	lowin voltage	V <sub>(BR)</sub> DSS	$I_D$ = 10 mA, $V_{GS}$ = –20 V	V 15		_	v
Gate threshold voltage	ge	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.3	_	2.5	V
Drain-source ON res	vistance	R <sub>DS (ON)</sub>	V <sub>GS</sub> = 4.0 V, I <sub>D</sub> = 2.5 A	_	43	60	
Diam-source ON les	sistance	R <sub>DS (ON)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2.5 A	— 30 40		40	mΩ
Forward transfer admittance		Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 2.5 A	5	10	_	S
Input capacitance		C <sub>iss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	600	_	pF
Reverse transfer capacitance		C <sub>rss</sub>		_	95	_	
Output capacitance		C <sub>oss</sub>		_	160	_	
Switching time	Rise time	tr	$V_{GS} = 2.5 \text{ A}$ $V_{GS} = 2.5 \text{ A}$ $V_{OUT} = 2.5 \text{ A}$	_	4	_	- ns
	Turn-ON time	t <sub>on</sub>		_	10	_	
	Fall time	t <sub>f</sub>			9	_	
	Turn-OFF time	t <sub>off</sub>	Duty $\leq$ 1%, $t_{W}$ = 10 $\mu s$	_	35	_	
Total gate charge (Gate-source plus gate-drain)		Qg	V <sub>DD</sub> ≈ 24 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 5 A	_	15	_	
Gate-source charge		Q <sub>gs</sub>			11	—	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>		—	4	—	

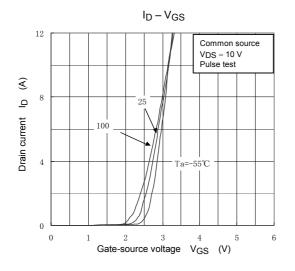
# Source–Drain Ratings and Characteristics (Ta = 25°C)

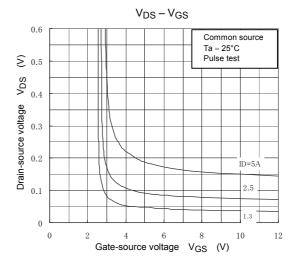
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	—	_	_	20	А
Forward voltage (diode)		V <sub>DSF</sub>	I <sub>DR</sub> = 5 A, V <sub>GS</sub> = 0 V	_	_	-1.2	V

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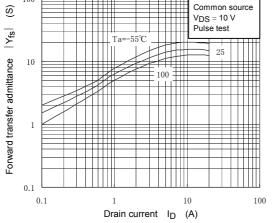


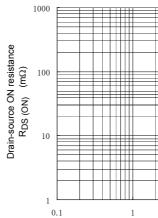






100





1

Drain current ID (A)



100

Common source Ta = 25°C

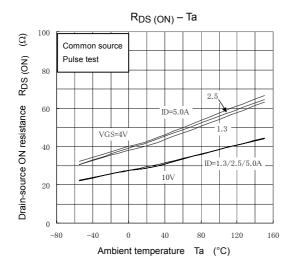
Pulse test

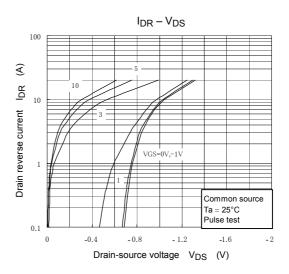
10

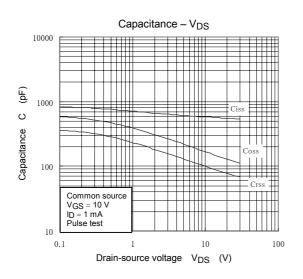
VGS=4\ 

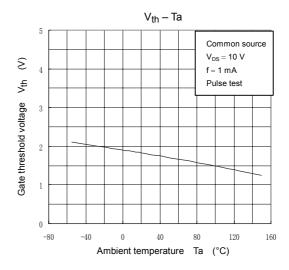
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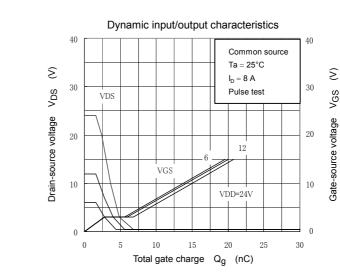
# TOSHIBA

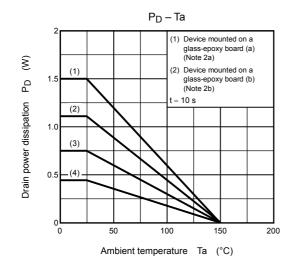


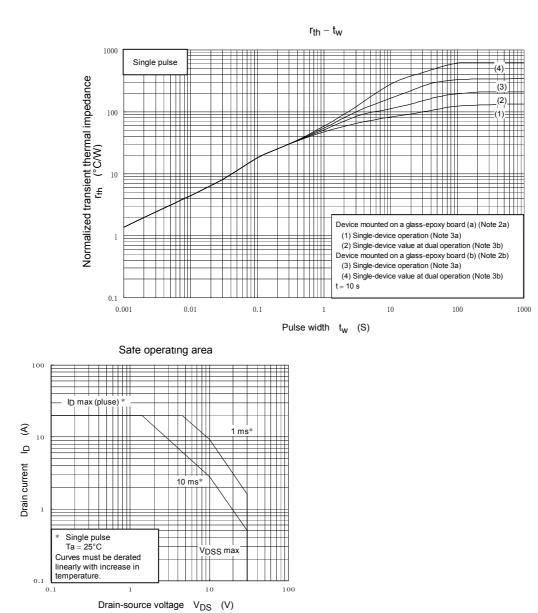












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